

TRANSMISSION ELECTRON MICROSCOPE (TEM)

MANUFACTURER : JEOL

MODEL : JSM 2100-F

Samples

- Samples are prepared with an Focused Ion Beam dedicated to the preparation of thin lamellas

Analysis

- High Resolution Imaging (dark and light background)
- Equipped with Field Effect Gun working with an acceleration voltage of 200 kV and 100 kV
- Lateral resolution : 0.19 nm

Characteristics

- Instrument unique in Canada, equipped with a Field Effect Gun capable of a very high resolution for imaging, X-ray mapping and PEELS

VARIANTS

Energy Dispersive Xray Spectrometry (EDS) for chemical analysis

- Qualitative and quantitative analysis
- Mapping possible

Parallel Electron Energy Loss Spectroscopy (PEELS) for chemical analysis and thickness measurement

- Qualitative and quantitative analysis
- Mapping possible

Crystallographic analysis